

Search Notes

Application/Control No.

10/804,153

Examiner

Erin D. Chiem

Applicant(s)/Patent under
Reexamination

HANASHIMA ET AL.

Art Unit

2883

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Google search: "photomask waveguide tutorial pattern width"	9/27/2005	EDC
Inventorship search	9/27/2005	EDC
385/\$.ccls. and text search	9/27/2005	EDC
Consulted Brian Healy	9/27/2005	EDC